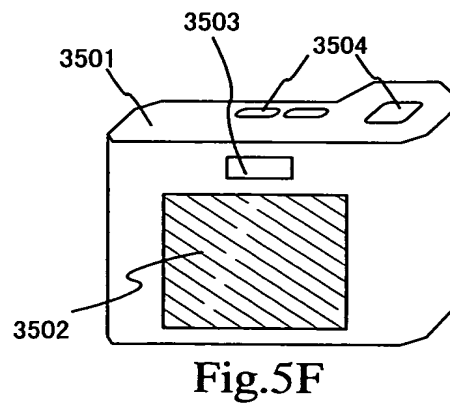
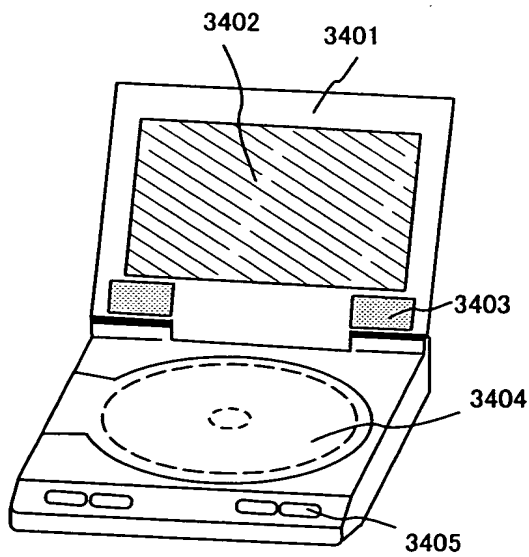
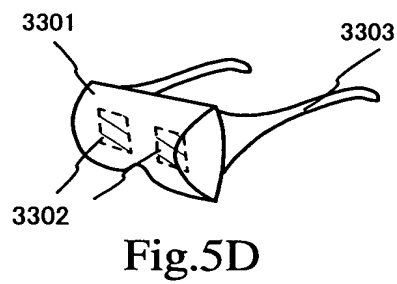
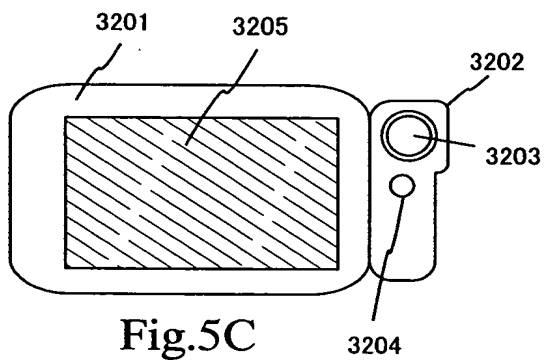
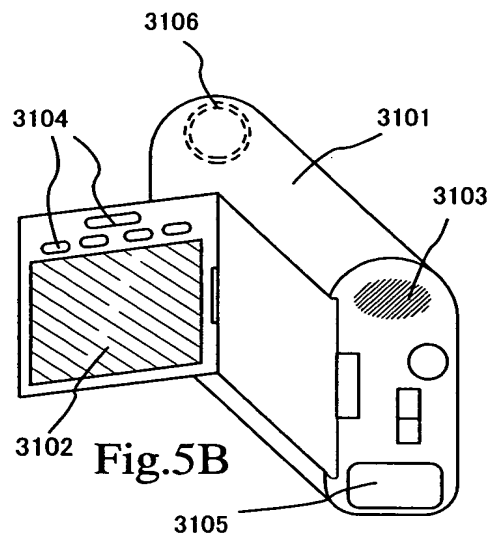
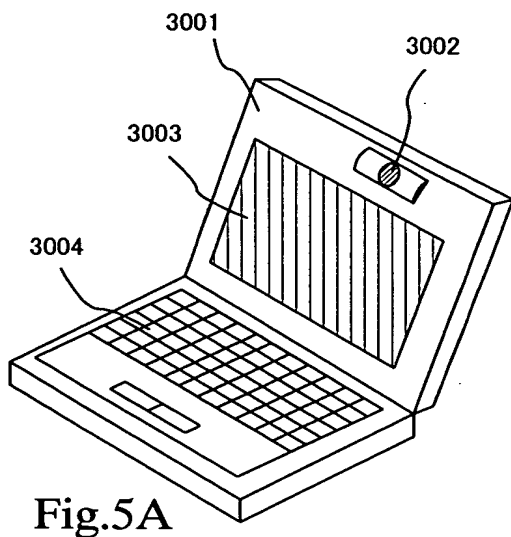


Concentration of Ni in Semiconductor Film in Depth Direction
(sample structure: cap a-Si/poly-Si/SiON/SiNO//glass)

Fig.4



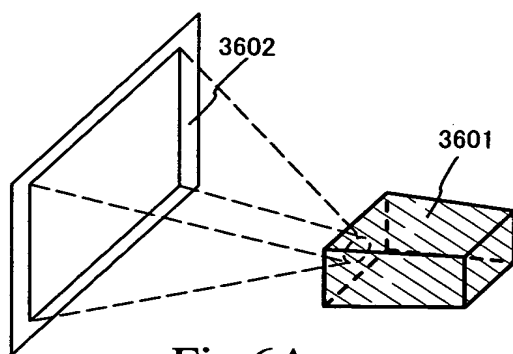


Fig. 6A

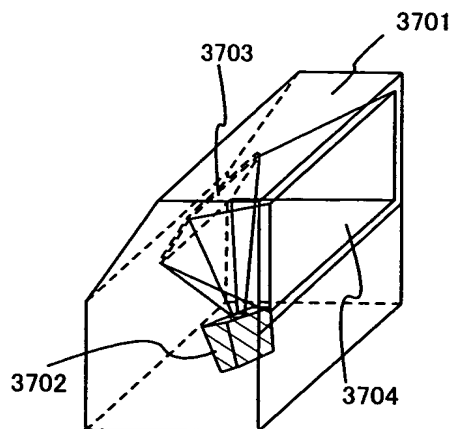


Fig. 6B

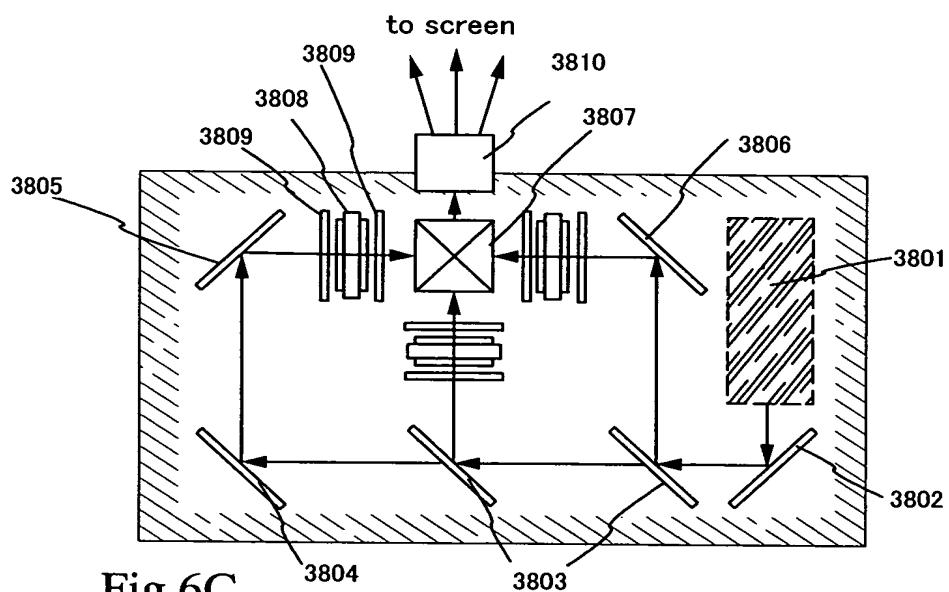


Fig. 6C

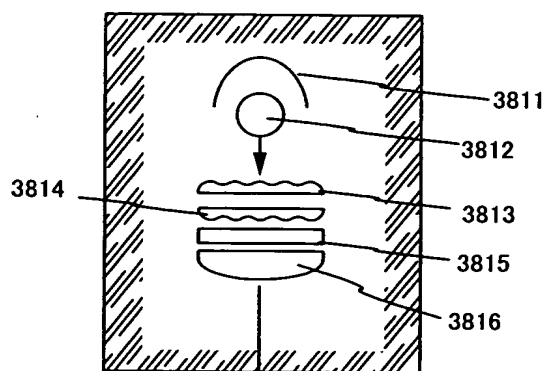


Fig. 6D

